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Records contain bibliographic data, abstract, title in English, French and German and legal status information. Full-text of detailed description and claims are given in one of EPO's official languages English, German or French for published unexamined applications (A-documents) from 1987 to date and for examined granted patents (B-documents) since 1991. Claims can be accessed for A-documents in English, German or French, for B-documents in all three languages. Abstracts in the original language can be searched for all A-documents. Patent, application, priority and related patent information, cited references, abstracts, detailed descriptions, claims and legal status information may all be searched. A thesaurus is available in the /IPC field.

All data featuring the same application number are grouped together in one single document. Bibliographic data and legal status information correspond to the European Patent Bulletin and EPOLINE Register.

SUBJECT COVERAGE

All patent-relevant areas of science and technology, i.e., all classes of the International Patent Classification.

SOURCES

Patent applications and granted patents published by the European Patent Office.

FILE DATA

- 1978 to the present (06/08): more than 2.4 million records
- Updated weekly
- Automatic current-awareness searches (SDIs) are run weekly

PRODUCER

European Patent Office
Vienna Sub Office
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PRODUCER/SUPPLIER

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76012 Karlsruhe
Germany
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Fax: +49 7247 808-131
E-mail: helpdesk@fiz-karlsruhe.de

Copyright Holders: European Patent Office and FIZ Karlsruhe

USER AIDS

- Online Helps (HELP DIRECTORY lists all help messages available)
- STNGUIDE

SEARCH AND DISPLAY FIELDS

Search Field Name	Search Code	Search Examples	Display Code
Basic Index (contains single words from the abstract (AB), claims (CLM), detailed description (DETD), and title (TI) fields) 1)	None or /BI	S PRINTED-CIRCUIT BOAR S STRIPPING DEVICE/BI S HOLOGRA?(S)?LASER?	AB, CLMEN, CLMDE, CLMFR, DETDDE, DETDEN, DETDFR, TIEN, TIDE, TIFR ABDE, ABEN, ABFR, AI
Abstract	/AB	S PLATIN? CATALYST?/AB	AI
Application Country (WIPO code and text)	/AC	S EP/AC	AI
Application Date 2)	/AD	S AD=JAN 2003	AI
Agent 3)	/AG	S ROBERT WEYDERT/AG	AG
Agent, Country (WIPO code and text)	/AG.CNY	S AUSTRIA/AG.CNY	AG
Agent, City 3)	/AG.CTY	S AACHEN/AG.CTY	AG
Agent, Street 3)	/AG.STR	S SEELBERGSTRASSE/AG.STR	AG
Agent Address 3)	/AGA	S MANNHEIM/AGA	AG
Agent Address Old 3)	/AGAO	S GULDE BERLIN/AGAO	LSEP.M
Agent Number	/AGN	S 241/AGN	AGN
Accession Number	/AN	S 2000:100003/AN	AN
Application Number	4) /AP (/APPS)	S EP1996-300599/AP	AI
Application Year 2)	/AY	S 1999-2000/AY	AI
Claims 1)	/CLM	S OFFICE CHAIR/CLM S BUEROSTUHL/CLM S PROCEDE DE TEINTURE/CLM	CLMEN, CLMDE, CLMFR CLMN
Number of Claims 2)	/CLMN	S CLMN<=10	CLMN
Number of Detailed Description 2)	/DETN	S DETN>1000	DETN
Designated States (WIPO code and text)	/DS	S BELGIUM/DS S BE/DS	DS
Document Type (code and text)	/DT	S P/DT	DT
Data Update Date 2)	/DUPD	S DUPD=FEB 2003	DUPD
Data Update Week 2)	/DUPW (/UW)	S 200409/DUPW	DUPW
Entry Date 2)	/ED	S ED>AUG 2004	ED
Entry Date Patent 2)	/EDP	S EDP = DEC 2004	EDP
Field Availability	/FA	S CLMDE/FA	FA
IPC (International Patent Classification)	/IC	S H05K007-14/IC	IC
IPC Edition	/IC.VER	S 7/IC.VER	IC.VER
IPC, Additional	/ICA	S F16H061-14/ICA	ICA, IC
IPC, Index (complementary)	/ICI	S B29K105-08/ICI S A61K031:40/ICI	ICI, IC
IPC, Main	/ICM	S C09K007-02/ICM	ICM, IC
IPC Old (contains old ICM, ICS, ICA, ICI)	/ICO	S A01B043-00/ICO	LSEP.M
IPC, Secondary	/ICS	S D21C011-04/ICS	ICS, IC
Inventor	/IN (/AU)	S MAYER ADOLF/IN	IN
Inventor Address, Country (WIPO code and text)	/IN.CNY	S DE/IN.CNY	IN
Inventor, Comment	/IN.COM	S THE OTHER INVENTORS HAVE AGREED TO WAIVE THEIR ENTITLEMENT TO DESIGNATION/IN.COM	IN

- 1) In addition to right truncation, simultaneous left and right truncation are available in this field. At least 4 characters need to be used for the length of the stem.
- 2) Numeric search field that may be searched using numeric operators or ranges.
- 3) Search with implied (S) proximity is available in this field.
- 4) Either STN format or Derwent format may be used.

SEARCH AND DISPLAY FIELDS (continued)

Search Field Name	Search Code	Search Examples	Display Code	
Inventor Address, City	3)	/IN.CTY	S WIEN/IN.CTY	IN
Inventor Address, Street	3)	/IN.STR	S BERLINER?/IN.STR	IN
Inventor Address		/INA	S MUENCHEN MURNAUER/INA	IN
Inventor Address Old	3)	/INAO	S S KRANZ/INAO	LSEP.M
International Patent Classification (contains ICM, ICS, ICA, ICI, IPCI, IPCR)	5)	/IPC	S A01B0001-02/IPC S H05B0006-36+NT/IPC S H05B0006-36-H05B0006-44/IPC	IPC
IPC, Action Date		/IPC.ACD	S 13 JAN 2006/IPC.ACD	IPC.TAB
IPC, Keyword Terms		/IPC.KW	S C12N0009/IPC (S) I/IPC.KW	IPC.TAB
IPC, Version from IPC		/IPC.VER	S 200601/IPC.VER	IPC.TAB
IPC, Initial		/IPCI	S H01L0023-29/IPCI	IPCI
IPC, Reclassified		/IPCR	S C08L0061-00/IPCR	IPCR
Language (ISO code and text)		/LA	S DE/LA S GERMAN/LA	LA
Language of Filing (ISO code and text)		/LAF	S FR/LAF S FRENCH/LAF	LAF
Language of Procedure (ISO code and text)		/LAP	S GERMAN/LAP	LAP
Licensee Name	3)	/LI	S CANDESCENT TECHNOLOGIES CORPORATION/LI	LI
Licensee Address, Country (WIPO code and text)	3)	/LI.CNY	S CA/LI.CNY	LI
Licensee Address, City	3)	/LI.CTY	S LONDON W3/LI.CTY	LI
Licensee Address, Street	3)	/LI.STR	S AM HARDTWALD/LI.STR	LI
Licensee Address	3)	/LIA	S US/LIA S SAINT PIENCE/LIA	LI
Licensee Address Old	3)	/LIAO	S INTERMUNE CALIFORNIA	LSEP.M
Licensee Date		/LID	S 20010901-20010930/LID	LI
Licensee Designated States Concerned (WIPO code and text)		/LIDS	S BE/LIDS S CYPRUS/LIDS	LI
Licensee Kind		/LIK	S E/LIK	LI
Licensee EPO Number		/LIN	S 7510/LIN	LI
Legal Status Code (code and text)		/LSC	S EPB235/LSC	LSEP
Legal Status Publication Date		/LSD	S 20050202/LSD	LSEP
Legal Status Date in Force		/LSDF	S LSDF=1978	LSEP
Legal Status Country (WIPO code and text)		/LSCY	S BE/LSCY	LSEP
Legal Status Publication Year		/LSPY	S 2000/LSPY	LSEP
Legal Status Code Text		/LSTX	S REFUSAL OF APPLICATION/LSTX	LSEP
Main Claim		/MCLM	S KUNSTSTOFFABFALL?/MCLM	MCLM
IPC Main Group Range Searchable	2,6)	/MGR	S B29K/ICI(T)20-30/MGR	ICM, ICS
Opponent Name	3)	/OP	S AMGEN/OP	OP
Opponent Address, Country		/OP.CNY	S US/OP.CNY	OP
Opponent Address, City		/OP.CTY	S THOUSAND OAKS/OP.CTY	OP
Opposition, Date of Rejection		/OP.RD	S 2003 AUGUST/OP.RD	OP
Opponent Address, Street	3)	/OP.STR	S DEHAVILLAND DRIVE/OP.STR	OP
Opposition, Date of Termination		/OP.TD	S 20041017/OP.TD	OP
Opponent Assignee (complete information)	3)	/OPA	S AMGEN THOUSAND OAKS/OPA	OP
Opponent Agent	3)	/OPAG	S VOGELSANG/OPAG	OP
Opponent Agent, Country		/OPAG.CNY	S DENMARK/OPAG.CNY	OP
Opponent Agent, City		/OPAG.CTY	S ABINGDON/OPAG.CTY	OP
Opponent Agent, Street	3)	/OPAG.STR	S BERLINER ALLEE/OPAG.STR	OP

2) Numeric search field that may be searched with numeric operators or ranges.

3) Search with implied (S) proximity is available in this field.

5) A thesaurus is available in this field.

6) Only valid for IPC version 1-7.

SEARCH AND DISPLAY FIELDS (continued)

Search Field Name	Search Code	Search Examples	Display Code
Opponent Agent Address	3) /OPAGA	S MUENCHEN/OPAGA	OP
Opponent Agent Number	/OPAGN	S 72473/OPAGN	OP
Opponent Agent Address Old	3) /OPAGAO	S (ABB SCHWEIZ)/OPAGAO	LSEP.M
Opponent Old	3) /OPAO	S AVECIA MANCHESTER/OPAO	OP
Opposition Date	/OPD	S 19970101-19981231/OPD	OP
Opposition Kind	/OPK	S OPPOSITION WITHDRAWN/OPK	OP
Opponent Number	/OPN	S 80/OPN	OP
Patent Assignee	3) /PA (/CS)	S BASF LACKE/PA	PA
Patent Assignee, Country (WIPO code and text)	/PA.CNY	S NL/PA.CNY	PA
Patent Assignee, City	3) /PA.CTY	S MANCHESTER/PA.CTY	PA
Patent Assignee, Designated States (WIPO code)	/PA.DS	S GB/PA.DS	PA
Patent Assignee, Street	3) /PA.STR	S VICTORIA STREET/PA.STR	PA
Patent Assignee Address	3) /PAA (/PADD)	S IRELAND/PAA	PA
Patent Assignee Address Old	3) /PAAO	S UNILEVER LONDON/PAAO	LSEP.M
Patent Assignee Number	/PAN	S 631710/PAN	PN
Patent Country (WIPO code and text)	/PC	S WO/PC	PI
Publication Date	2) /PD	S PD=5 FEB 2004	PI
Patent Information Publication Type	/PIT	S EPB2 AMENDED PATENT	PIT
Patent Kind Code	/PK	S EPB1/PK	PI
Patent Number	4) /PN (/PATS)	S EP140038/PN S EP-----140038/PN	PI
Priority Country (WIPO code and text)	/PRC	S AUSTRALIA/PRC	PRAI
Priority Country, Original	/PRCO	S BELGIUM/PRCO	
Priority Date	2) /PRD	S JP/PRC AND 19880101-19880331/PRD S 1980US-0167554/PRD	PRAI
Priority Date, First	2) /PRDF	S 20030109/PRDF	PRAI
Priority Number	4) /PRN	S US1986-817951/PRN	PRAI
Priority Number, Old	4) /PRN.OLD	S AT1944-1352/PRN.OLD	LSEP.M
Priority Number, Original	/PRNO	S UA2003-3065259/PRNO	PRAO
Priority Year	2) /PRY	S PRY=2003	PRAI
Priority Year, First	2) /PRYF	S PRYF=2003	PRAI
Publication Year	/PY	S 1999-2000/PY	PI
Referenced Non-Patent Literature	/REN	S SCIENCE/REN	REN
Related Application Country	/RLC	S EP/RLC	RLI
Related Application Date	/RLD	S RLD>JAN 2003	RLI
Related Application Number	/RLN	S EP1995-104274/RLN	RLI
Related Patent Country	/RLPC	S US/RLPC	RLI
Related Patent Number	/RLPN	S EP662724/RLPN	RLI
Referenced Patent Country	/RPC	S US/RPC	REP
Referenced Patent Number, Original	/RPNO (/RPN)	S "US-A-3 615 881"/RPNO	REP
Related Application Type	/RLT	S EARLIER APPLICATION/RLT	RLI
IPC Sub Group Range Searchable	2,6) /SGR	S H05K007/ICM(S)10000-20000/SGR	ICM, ICS

2) Numeric search field that may be searched with numeric operators or ranges.

3) Search with implied (S) proximity is available in this field.

4) Either STN format or Derwent format may be used.

6) Only valid for IPC version 1-7.

SEARCH AND DISPLAY FIELDS (continued)

Search Field Name	Search Code	Search Examples	Display Code
Title (contains TIEN, TIDE, TIFR)	/TI	S ABISOLIERGERAET/TI S DISPOSITIF DE DENUDAGE/TI	TIEN, TIFR, TIDE
Title Old	/TIO	S DEVICE FOR MANAGING/TIO	LSEP.M
Title Language (ISO code and text)	/TL	S L1 AND ENGLISH/TL	TL
Update Date	2) /UP	S UP=JAN 2005	UP
Legal Status Update Date	/UPLS	S 20050209/UPLS	UPLS
Update Week	2) /UW	S L1 AND UW<200409	UW

2) Numeric search field that may be searched using numeric operators or ranges.

Super Search Fields 1)

Search Field Name	Search Code	Fields Searched	Search Examples	Display Codes
Patent Countries Short Basic Index	/PCS /SBI	/DS, /PC /AB, /MCLM, /TI	S EP/PCS S ANATOMIE/SBI	PC, DS AB, TI, MCLM

1) Enter a super search code to execute a search in one or more fields that may contain the desired information. Super search fields facilitate crossfile and multifile searching. EXPAND may not be used with super search fields. Use EXPAND with the individual field codes instead.

IPC Thesaurus

The classifications, validity and catchwords for the main headings and subheadings from the current (8th) edition of the WIPO International Patent Classification (IPC) manual are available. The classifications from the previous editions (1-7) are also available as separate thesauri. To EXPAND and SEARCH in the thesauri for editions 1-8, use the field code followed by the edition number, e.g., /IPC2 for the 2nd edition. Catchwords are included only in the thesauri for the 8th, 7th, 6th, and 5th editions.

Code	Content	Examples
ADVANCED (ADV)	Advanced Level Codes for the Core Level IPC Code	E A61K0006-02+ADVANCED/IPC
ALL	All Associated Terms (BT, SELF, NT, RT)	E C01C003-00+ALL/IPC
BRO (MAN)	Complete Class	E C01C+BRO/IPC
BT	Broader Term (SELF, BT)	E C01F001-00+BT/IPC
CORE (COR)	Core Codes for the Advanced Level IPC Code	E G08C0019-22+CORE/IPC
ED	Complete title of the SELF term and IPC manual	E C01F001-00+ED/IPC
HIE	Hierarchy Term (Broader and Narrower Term) (BT, SELF, NT)	E C011003-00+HIE/IPC
INDEX	Complete title of the SELF term	E C01F001-00+INDEX/IPC
KT	Keyword Term (catchwords) (SELF, KT)	E CYANOGEN+KT/IPC
NEXT	Next Classification	E C01C001-00+NEXT5/IPC
NT	Narrower Terms (SELF, NT)	E C01C+NT/IPC
PREVn	Previous Classification (n =1,2,...)	S A01B0001-06+NT/IPC
RT (SIB)	Related Terms (SELF, RT)	E C01C001-12+PREV10/IPC
TI	Complete Title of the SELF Term and Broader Terms (BT, SELF)	E C01C003-20+RT/IPC E C01F001-00+TI/IPC

DISPLAY AND PRINT FORMATS

Any combination of display fields and formats may be used to display or print answers. Multiple codes must be separated by commas or spaces, e.g. 'D L1 1-5 TI PI'. The fields are displayed or printed in the order requested.

Hit-term highlighting is available for all fields. Highlighting must be ON during SEARCH in order to use the HIT, KWIC, and OCC formats.

More information about display fields for specific types of information is available by typing one of the following 'HELP' commands at an arrow prompt (=>) in the EPFULL database:

- HELP DFIELDS - lists all valid custom formats
- HELP EFIELDS - lists all selectable fields
- HELP FORMATS - lists valid predefined formats
- HELP SRTFIELDS - lists valid sort fields

Format	Definition	Examples
AB.M (AB)	Abstract for all Publication Levels in all Languages	
AB.PK 2)	Abstract for a Certain Publication Level in all Languages	D AB
ABDE.M (ABDE)	Abstract for all Publication Levels in German	
ABDE.PK 2)	Abstract for a Certain Publication Level in German	D ABDE.PK
ABEN.M (ABEN)	Abstract for all Publication Levels in English	
ABEN.PK 2)	Abstract for a Certain Publication Level in English	
ABFR.M (ABFR)	Abstract for all Publication Levels in French	
ABFR.PK 2)	Abstract for a Certain Publication Level in French	
AG	Agent	
AGN	Agent Number	
AI (AP) 1)	Application Information	D AI PRAI 5
AI.M	Application Information for all Publication Levels	
AN	Accession Number	
CLM	Claims	
CLM.M	Claims for all Publication Levels in all avail. Languages	D CLM.M
CLM.PK 2)	Claims for a Certain Publ. Level in all Languages	D CLM.A1
CLM.PK(n) 2)	Claim Number n for a Certain Publ. Level in all Lang.	D CLM.B1(1)
CLMDE	Claims in German	D CLMDE
CLMDE.M	All Claims for all Publication Levels in German	D CLMDE.M
CLMDE.PK 2)	All Claims for a Certain Publication Level in German	D CLMDE.A2
CLMDE.PK(n) 2)	Claim Number n for a Certain Publ. Level in German	
CLMDE(n)	Claim n in German	
CLMEN	Claims in English	D CLMEN
CLMEN.M	All Claims for all Publication Levels in English	D CLMEN.M
CLMEN.PK 2)	All Claims for a Certain Publication Level in English	D CLMEN.B2
CLMEN.PK(n) 2)	Claim Number n for a Certain Publ. Level in English	
CLMEN(n)	Claim n in English	
CLMFR	Claims in French	D CLMFR
CLMFR.M	All Claims for all Publication Levels in French	D CLMFR.M
CLMFR.PK 2)	All Claims for a Certain Publication Level in French	D CLMFR.A1
CLMFR.PK(n) 2)	Claim Number n for a Certain Publ. Level in French	
CLMFR(n)	Claim n in French	
CLMN	Number of Claims	
CLMN.M	Number of Claims for all Publication Levels	D CLMN.M
DETD	Detailed Description	
DETDDE	Detailed Description in German	D DETDDE
DETDDE(n)	Detailed Description in German, Paragraph n	
DETDEN	Detailed Description in English	D DETDEN
DETDEN(n)	Detailed Description in English, Paragraph n	

1) Application and patent numbers are available in Derwent and STN format. The format for DISPLAY, PRINT, SELECT and SORT is set using the SET PATENT command. STN is the default format. Enter SET PAT DERWENT to change to the DERWENT format. To reset to the STN format, enter SET PAT STN.

2) PK = Patent Kind Code.

DISPLAY AND PRINT FORMATS

Format	Definition	Examples
DETDFR	Detailed Description in French	D DETDFR
DETDFR(n)	Detailed Description in French, Paragraph n	
DETN	Number of Detailed Descriptions	D DETN
DETN.M	Number of Detailed Descriptions for all Publication Lev	D DETN.M
DS	Designated States	
DT (TC)	Document Type	
DUPD	Data Update Date	D DUPD
DUPW (UW)	Data Update Week	
ED	Entry Date	D ED 1-10 L3
FA (FA.M)	Field Availability for all Publication Levels	D FA 1-20
IC	IPC	
IC.VER	IPC Edition	D IC.VER
ICA	IPC, Additional	
ICI	IPC, Index	
ICM	IPC, Main	
ICS	IPC, Secondary	
IN (AU)	Inventor	D TI IN 5
IPC	International Patent Classification	D IPC
IPCI	IPC, Initial	D IPCI
IPCR	IPC, Reclassified	D IPCR
LA	Language	
LA.M	Language of Publication for all Publication Levels	D LA.M
LAF	Language of Filing	
LAF.M	Language of Filing for all Publication Levels	D LAF.M
LAP	Language of Procedure	
LAP.M	Language of Procedure for all Publication Levels	D LAP.M
LI	Licensee Name	
LI.M	Licensee Name for all Publication Levels	D LI.M
LS	3) Legal Status (from the INPADOCDB database)	
LS2	3) Legal Status (from the INPADOCDB database), detailed version with display headers	
LSEP	EPFULL Legal Status	D LSEP
LSEP.M	EPFULL Legal Status with History	D LSEP.M
LSEPR	EPFULL Legal Status with History plus additional EP Register information via PDF link	D LSEPR
MCLM	Main Claim	D MCLM
MCLM.M	Main Claim for all Publication Levels in all avail. Lang.	D MCLM.M
MCLM.PK	2,3) Main Claim for a Certain Publication Level	
MCLMDE	Main Claim in German	D MCLMDE
MCLMDE.M	Main Claim for all Publication Levels in German	D MCLMDE.M
MCLMDE.PK	2,3) Main Claim for a Certain Publication Level in German	
MCLMEN	Main Claim in English	D MCLMEN
MCLMEN.M	Main Claim for all Publication Levels in English	D MCLMEN.M
MCLMEN.PK	2,3) Main Claim for a Certain Publication Level in English	
MCLMFR	Main Claim in French	D MCLMFR
MCLMFR.M	Main Claim for all Publication Levels in French	D MCLMFR.M
MCLMFR.PK	2,3) Main Claim for a Certain Publication Level in French	D MCLMFR.PK
OP	Opponent Name	
OP.M	Opponent Name for all Publication Levels	D OP.M
PA	Patent Assignee	
PAN	Patent Assignee Number	D PAN
PI (PN)	1) Patent Information	
PI.M (PN.M)	1) Patent Information for all Publication Levels	D PI.M
PIT	Patent Information Publication Type	
PIT.M	Patent Information Publication Type for all Publ. Levels	D PIT.M
PRAI (PRN)	1) Priority Information, Original	
PRAI.M	1) Priority Information for all Publication Levels	D PRAI.M

1) Application and patent numbers are available in Derwent and STN format. The format for DISPLAY, PRINT, SELECT and SORT is set using the SET PATENT command. STN is the default format. Enter SET PAT DERWENT to change to the DERWENT format. To reset to the STN format, enter SET PAT STN.

2) PK = Patent Kind Code.

3) Custom display only.

DISPLAY AND PRINT FORMATS (continued)

Format	Definition	Examples
PRAO REN REN.M REP REP.M RLAP.M RLI RLI.M RLPN.M TI TI.M TIDE TIDE.M TIEN TIEN.M TIFR TIFR.M TL TL.M UP	Priority Number, Original Format Referenced Non-Patent Literature Referenced Non-Patent Literature for all Publication Lev. Referenced Patent Referenced Patent for all Publication Levels Related Application: Application Number for all Publ. Lev. Related Application Information Related Application Information for all Publication Lev. Related Application: Publication Number for all Publ. Lev Title (contains TIEN, TIFR, TIDE Titles for all Publication Levels Title in German Title in German for all Publication Levels Title in English Title in English for all Publication Levels Title in French Title in French for all Publication Levels Title Language Title Language for all Publication Levels Update Date	D REN D REN.M D REP.M D RLI D RLI.M D RLPN.M D TIDE D TIDE.M D TIEN 1-3 D TIEN.M D TIFR.M D TL.M
ALL ALL.M ALL.PK DALL DALL.M IALL IALL.M IALL.PK APPS BIB BIB.M BIB.PK IBIB IBIB.M IBIB.PK BIBLS BIBLS.M BRIEF BRIEF.M BRIEF.PK IBRIEF IBRIEF.M IBRIEF.PK	1) AN, ED, UP, DUPD, DUPW, TI, IN, PA, PAN, AG, AGN, LAF, LA, LAP, TL, DT, PIT, PI, DS, AI, RLI, PRAI, REN, REP, IPC, OP, LI, AB, DETD, CLM 1) ALL, for all publication levels 1,2) ALL, for a certain publication level 1) ALL, with delimiter for post-processing 1) ALL.M, with delimiter for post-processing 1) ALL, indented with text labels 1) ALL.M, indented with text labels 1,2) ALL.PK, indented with text labels 1) AI, PRAI 1) AN, ED, UP, DUPD, DUPW, TI, IN, PA, PAN, AG, AGN, LAF, LA, LAP, TL, DT, PIT, PI, DS, AI, RLI, PRAI, REN, REP 1) BIB, for all publication levels 1,2) BIB, for a certain publication level 1) BIB, indented with text labels 1) BIB.M, indented with text labels 1,2) BIB.PK, indented with text labels BIB, LSEP BIB, LSEP.M 1) AN, ED, UP, DUPD, DUPW, TI, IN, PA, PAN, AG, AGN, LAF, LA, LAP, TL, DT, PIT, PI, DS, AI, RLI, PRAI, REN, REP IPC, AB, MCLM 1) BRIEF, for all publication levels 1,2) BRIEF, for a certain publication level 1) BRIEF, indented with text labels 1) BRIEF.M, indented with text labels 1,2) BRIEF.PK, indented with text labels	D ALL D ALL.M D ALL.A1 D DALL D DALL.M D IALL D IALL.M D IALL.B2 D BIB D BIB.M D BIB.B2 D IBIB D IBIB.M D IBIB.B2 D BIBLS D BRIEF D BRIEF.M D BRIEF.A1 D IBRIEF.M D IBRIEF.B2
IC IND (IPC) IND.M (IPC.M) IPC.TAB IPC.TAB.M MAX	ICM, ICS IC.VER, ICM, ICS, ICA, ICI, IPCR, IPCI IPCI, IPCR (for all publication levels) IPC, IPC.KW, IPC.ACD, IPC.VER in tabular format IPC.TAB for all levels 1) AN, ED, UP, DUPD, DUPW, TI, IN, PA, PAN, AG, AGN, LAF, LA, LAP, TL, DT, PIT, PI, DS, AI, RLI, PRAI, REN, REP, IPC, OP, LI, AB, DETD, CLM, LSEP.M (for all publ. levels)	D IND D IND.M D MAX

- 1) By default, patent numbers, application and priority numbers are displayed in STN format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN format, enter SET PATENT STN.
2) PK= Patent Kind Code.

DISPLAY AND PRINT FORMATS (continued)

Format	Definition	Examples
IMAX 1)	MAX, indented with text labels	D IMAX
FAM	AN, table of patent family information (from the INPADOCDB database)	
CFAM	Condensed family format (from the INPADOCDB database)	D CFAM
TRIAL, TRI, SAMPLE, FREE	TI, FA, DETD, CLMN (for all publication levels)	
SCAN 3)	TI (random display without answer number)	D SCAN
STD	AN, ED, UP, DUPD, DUPW, TI, IN, PA, PAN, AG, AGN, REN, REP, LAF, LA, LAP, TL, DT, PIT, PI, DS, AI, PRAI, RLI, IPC	D STD
STD.M	STD, for all publication levels (STD.M is the default)	
STD.PK 1,2)	STD, for a certain publication level	D STD.A1
ISTD 1)	STD, indented with text labels	D ISTD
ISTD.M 1)	STD.M, indented with text labels	D ISTD.M
ISTD.PK 1,2)	STD.PK, indented with text labels	D ISTD.A1
TX	DETD, CLM	D TX
TX.M	DETD, CLM (for all publication levels)	D TX.M
TX.PK	DETD, CLM (for a certain publication level)	D TX.B2
HIT	Hit-term(s) and field(s)	D HIT
KWIC	Up to 50 words before and after hit-term(s) (KeyWord-In-Context)	D KWIC
OCC	Number of occurrences of hit-term(s) and field(s) in which they occur	D OCC

- 1) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.
- 2) PK = Patent Kind Code.
- 3) SCAN must be specified on the command line, i.e., D SCAN or DISPLAY SCAN.

SELECT, ANALYZE, AND SORT CODES

The SELECT command is used to create E-numbered or L-numbered lists of terms taken from the specified field(s) in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphanumeric (A) or numeric (N) order of the specified field(s).

Definition	Code	Analyze/ Select 1)	Sort
Abstract	AB	x	-
Abstract in German	ABDE	x 2)	-
Abstract in English	ABEN	x 2)	-
Abstract in French	ABFR	x 2)	-
Application Country	AC	x	A
Application Date	AD	x	N
Agent	AG	x	A
Agent, Country	AG.CNY	x	A
Agent for all Publication Levels	AG.M	x	A
Agent Name and Address	AGDD	x	-
Application Information	AI (AP, APPS)	x	A
Application Information for all Publication Levels	AI.M	x	A
Accession Number	AN	x	A
Application Year	AY	x	N
Claims	CLM	x	-
All Claims for all Publication Levels in available Language	CLM.M	x	-
All Claims for a Certain Publication Level in English	CLM.PK 3)	x	-

- 1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT IN.
- 2) Appends /AB to the terms created by SELECT.
- 3) PK = Patent Kind Code

SELECT, ANALYZE, AND SORT CODES

Definition	Code	Analyze/ Select 1)	Sort
Claim Number n for a Cert. Publication Level. in all Languages	CLM.PK(n) 3)	x	-
Claim in German	CLMDE	x	-
Claim n in German	CLMDE(n)	x	-
All Claims for all Publication Levels in German	CLMDE.M	x	-
All Claims for a Certain Publ. Level in German	CLMDE.PK 3)	x	-
Claim Number n for a Cert. Publication Level in German	CLMDE.PK(n) 3)	x	-
Claim in English	CLMEN	x	-
Claim n in English	CLMEN(n)	x	-
All Claims for all Publication Levels in English	CLMEN.M	x	-
All Claims for a Certain Publication Level in English	CLMEN.PK 3)	x	-
Claim Number n for a Cert. Publication Level in English	CLMEN.PK(n) 3)	x	-
Claim in French	CLMFR	x	-
Claim n in French	CLMFR(n)	x	-
All Claims for all Publication Levels in French	CLMFR.M	x	-
All Claims for a Certain Publication Level in French	CLMFR.PK 3)	x	-
Claim Number n for a Cert. Publication Level in French	CLMFR.PK(n) 3)	x	-
Number of Claims	CLMN	x	-
Number of Claims for all Publication Levels	CLMN.M	x	-
Detailed Description	DETD	x	-
Detailed Description for all Publication Levels	DETD.M	x	-
Complete Detail. Description for Certain Publication Levels	DETD.PK	x	-
Paragraph Number n of Det. Description Cert. Publication	DETD.PK(n)	x	-
Detailed Description in German	DETDDE	x	-
Detailed Description in German, Paragraph n	DETDDE(n)	x	-
Detailed Description in English	DETDEN	x	-
Detailed Description in English, Paragraph n	DETDEN(n)	x	-
Detailed Description in French	DETDFR	x	-
Detailed Description in French, Paragraph n	DETDFR(n)	x	-
Number of Paragraphs in DET	DETN	x	-
Number of Paragraphs in DETD for all Publication Levels	DETN.M	x	-
Designated States	DS	x	-
Document Type	DT (TC)	x	A
Data Update Date	DUPD	x	N
Data Update Week	DUPW (UW)	x	N
Entry Date	ED	x	N
Field Availability	FA	x	-
IPC (Main and Secondary)	IC	x	-
IPC Edition	IC.VER	x	-
IPC, Main	ICM	x	A
IPC, Secondary	ICS	x	A
Inventor	IN (AU)	x	A
Inventor, Comment	IN.COM	x	-
Inventor Address, Country	IN.CNY	x	-
Inventor for all Publication Level	IN.M	x	A
Inventor Address	INA	x	-
Inventor Address, Complete Information	INDD	x	-
IPC (ICM, ICS, ICA, ICI, IPCI, IPCR)	IPC	x	-
IPC, Advanced Level Symbols	IPC.A	x	-
IPC, Core Level Symbols	IPC.C	x 4)	-
IPC, Core Level Symbols for Invention	IPC.CI	x 4)	-
Pre-IPC8 Symbols from the ICM and first IPC8 values from 2006 onwards	IPC.F	x 4)	A
IPC, Advanced Level Symbols for Invention	IPC.AI	x 4)	-

1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT TI.

3) PK = Patent Kind Code.

4) Appends /IPC to the terms created by SELECT.

SELECT, ANALYZE, AND SORT CODES (continued)

Definition	Code	Analyze/ Select 1)	Sort
International Patent Classification, Max	IPC.M	x	-
IPC, Initial	IPCI	x 4)	-
IPC, Reclassified	IPCR	x 4)	-
Language	LA	x	A
Language of Publication for all Publication Levels	LA.M	x	A
Language of Filing	LAF	x	A
Language of Filing for all Publication Levels	LAF.M	x	A
Language of Procedure	LAP	x	A
Language of Procedure for all Publication Levels	LAP.M	x	A
Licensee Name	LI	x	-
Licensee Address, Country	LI.CNY	x	-
Licensee Designated States Concerned	LI.DS	x	-
Licensee Name for all Publication Levels	LI.M	x	-
Licensee Date	LID	x	-
Licensee Kind	LIK	x	-
Licensee EPO Number	LIN	x	-
Legal Status: Withdrawal Date	LS.WD	x	N
Legal Status Code	LSC	x	-
Legal Status Country	LSCY	x	-
Legal Status Publication Date	LSD	x	-
Legal Status Date in Force	LSDF	x	-
EPFULL Legal Status	LSEP	x	A
EPFULL Legal Status with History	LSEP.M	x	A
Main Claim	MCLM	x	-
Main Claim in German	MCLMDE	x	-
Main Claim for all Publication Levels in German	MCLMDE.M	x	-
Main Claim in English	MCLMEN	x	-
Main Claim for all Publication Levels in English	MCLMEN.M	x	-
Main Claim in French	MCMLFR	x	-
Main Claim for all Publication Levels in French	MCLMFR.M	x	-
Opponent Name	OP	x	-
Opponent Address, Country	OP.CNY	x	-
Opponent Address, City	OP.CTY	x	-
Opponent Name for all Publication Levels	OP.M	x	-
Opposition, Date of Rejection	OP.RD	x	-
Opponent Address, Stree	OP.STR	x	-
Opposition, Date of Termination	OP.TD	x	-
Opponent Address	OPA	x	-
Opponent Agent	OPAG	x	-
Opponent Agent, Country	OPAG.CNY	x	A
Opponent Agent Address	OPAGA	x	-
Opponent Agent Number	OPAGN	x	-
Occurrence Count of Hit Terms	OCC	-	N
Opposition Date	OPD	x	-
Opponent Name and Adress	OPDD	x	-
Opposition Kind	OPK	x	-
Opponent Number	OPN	x	-
Patent Assignee	PA (CS)	x	A
Patent Assignee, Designated States	PA.DS	x	-
Patent Assignee, Country	PA.CNY	x	A
Patent Assignee Address	PAA	x	-
Patent Assignee Address, Complete Information	PADD	x	-
Patent Assignee, Number	PAN	x	A
Patent Number Group	PATS	x	-
Patent Country	PC	x	A
Patent Assignee for all Publication Levels	PA.M	x	A

- 1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT TI.
- 4) Appends /IPC to the terms created by SELECT.

SELECT, ANALYZE, AND SORT CODES (continued)

Definition	Code	Analyze/ Select 1)	Sort
Publication Date	PD	x	N
Publication Date for all Publication Levels	PD.M	x	-
Patent Information Publication Type	PIT	x	A
Patent Information Publ. Type for all Publ. Levels	PIT.M	x	A
Patent Kind Code	PK	x	A
Patent Kind Code for all Publication Levels	PK.M	x	A
Patent Number	PN (PI)	x	A
Patent Number for all Publication Levels	PN.M (PI.M)	x	-
Priority Country	PRC	x	A
Priority Country, Original	PRCO	x	A
Priority Date	PRD	x	N
Priority Number	PRN (PRAI)	x	A
Priority Number for all Publication Levels	PRN.M (PRAI.M)	x	-
Priority Number, Original	PRNO	x	A
Priority Year	PRY	x	N
Priority Year, First	PRYF	x	N
Publication Year	PY	x	N
Publication Year for all Publication Levels	PY.M	x	N
Referenced Non-Patent Literature	REN	x	-
Referenced Non-Patent Literature all Publ. Levels	REN.M	x	-
Referenced Patents	REP	x	-
Referenced Patent for all Publication Levels	REP.M	x	-
Related Application Country	RLC	x	-
Related Application Number	RLN	x	-
Related Application Number all Publication Levels	RLN.M	x	-
Related Patent Country	RLPC	x	-
Related Patent Number	RLPN	x	-
Related Patent Number for all Publication Levels	RLPN.M	x	-
Related Application Type	RLT	x	-
Subclass Group	SCG	x 5)	-
Subclass Group Additional	SCGA	x 6)	-
Subclass Group Main	SCGM	x 7)	-
Subclass Group Secondary	SCGS	x 8)	-
Subclass	SCL	x 5)	-
Subclass Additional	SCLA	x 6)	-
Subclass Main	SCLM	x 7)	-
Subclass Secondary	SCLS	x 8)	-
Title	TI	x 9) (default)	A
Title for all Publication Levels	TI.M	x	A
Title in German	TIDE	x	A
Title for all Publication Levels in German	TIDE.M	x	-
Title in English	TIEN	x	A
Title for all Publication Levels in English	TIEN.M	x	-
Title in French	TIFR	x	A
Title for all Publication Levels in French	TIFR.M	x	-
Title Language	TL	x	A
Title Language for all Publication Levels	TL.M	x	A
Legal Status Update Date	UPLS	x	-

- 1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT TI.
- 5) Appends /IC to the terms created by SELECT.
- 6) Appends /ICA to the terms created by SELECT.
- 7) Appends /ICM to the terms created by SELECT.
- 8) Appends /ICS to the terms created by SELECT.
- 9) Selects or analyzes TIEN, TIDE, and TIFR with /TI appended to the terms created by SELECT.

SAMPLE RECORDS

DISPLAY MAX (STN format)

AN 2005:72706 EPFULL EDP 20060316 ED 20060316 UP 20060316
 DUPD 20060315 DUPW 200611
 TIEN The way, the method of unrolling elastic material in the industry of
 expendable baby napkin production.
 TIFR La facon, le method de derouler de materiau elastique dans l' industrie
 pour la production de couche-coulotte jetable.
 TIDE Die Weise, das Verfahren von Abrollen von elastischem Material in der
 Industrie zum Herstellen von Wegwerf-Babywindeln.
 IN Borczuch, Lech Robert, Sienkiewicza 35, 05-220 Zielonka, PL
 PA Borczuch, Lech Robert, Sienkiewicza 35, 05-220 Zielonka, PL
 PAN 7048330
 DT Patent
 LAF Polish
 LA English
 LAP English
 TL German; English; French
 PIT EPA1 Application published with search report
 PI EP 1634557 A1 20060315
 DS AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HU IE IS IT LI LT LU MC NL PL
 PT RO SE SI SK TR
 EXTENSION STATES: AL BA HR LV MK YU
 AI EP 2005-460016 A 20050614
 PRAI PL 2004-369801 A 20040912
 IPCI A61F0013-15 [I,A]
 A61F0013-15 [I,C*]

ABEN

The method consists in application of the rule of unrolling elastic material (lycra elastic) from immovable, for example, conic shaped rollers in the industry of expendable baby napkin production. Immovable material with approachable endings enables inclusion of that material and bonding thereof in the course of a production line, so production process interruption is avoided and no costs related thereto are incurred. Currently, material rollers are movable and the process of bonding consists in interruption of a production process and in replacement of empty rollers with new ones on which material is rolled. PICTORIAL FIGURE. The substance of this reservation is the way, the method, so the drawing included hereafter presents only the proposed solution of feeding the material in the form of elastic used for production of expendable baby napkins. Without any detail construction specifications, dimensions or specific features being presented.

DETDEN

THE DESCRIPTION OF A SOLUTION

[0001] The method having been invented by me consists in application of the rule of unrolling elastic material (lycra elastic) from immovable, for example, conic shaped rollers in the industry of expendable baby napkin production. Immovable material with approachable endings enables inclusion of that material and bonding thereof in the course of a production line, so production process interruption is avoided and no costs related thereto are incurred. Until now, the method of partly unapproachable, movable rollers replaceable during a production line stoppage has been employed. Figure 1: The Pictorial Presentation of the Heretofore Method (publication is not allowed). The idea of application of immovable rollers instead of movable ones enables continuity of a production process which translates directly into remarkable reduction of costs and contributes to impressive productivity ratio increase. New conic-shaped rollers should be located in an approachable place, so binding of the ending of material being unrolled with the beginning of prepared material could be possible. Figure 2: The Pictorial Presentation of the New Method of Material Feeding for Production. The solution can be utilized by an industry and the outcome of it is reduction of production costs resulting from assurance of production continuity based on art. 27.

CLMEN

1. Application No.: The way, the method of unrolling elastic material in the industry of expendable baby napkin production, that is subjected to reservation and right protection, defines the following action: bonding (for example, by means of binding or gluing) elastic material in the progress of a production cycle and in the progress of material unrolling with the use of immovable, connectable rollers for material instead of movable ones.

LEGAL STATUS INCLUDING HISTORY

AN 2005:72706 EPFULL
 20060315 EPB430 Unexamined document without grant, (first publication)
 2006031520060316
 20060315 EPB840 Designated contracting states
 AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HU IE IS IT LI LT
 LU MC NL PL PT RO SE SI SK TR
 EP 1634557 A1 20060315
20060316
 20060315 EPB844EP Extension of the European patent to
 AL BA HR LV MK YU
20060316

DISPLAY BRIEF (Derwent format)

AN 2005:65026 EPFULL EDP 20060223 ED 20060223 UP 20060223
 DUPD 20060215 DUPW 200607
 TIEN Wheelbarrow.
 TIFR Brouette.
 TIDE Schubkarre.
 IN Lim, Fong Kan, Lot 39, Rawang Industrial Estate, 16 1/2 Miles, Jalan
 Ipoh, 48000 Rawang Selangor, MY
 PA Prestar Manufacturing SDN BHD, Lot 39, Rawang Industrial Estate 16 1/2
 Miles, Jalan Ipoh, 48000 Rawang, Selangor, MY
 PAN 7106830
 AG Danek, Vilem, Vinohradska 45, 12000 Praha, CZ
 AGN 9204801
 DT Patent
 LAF English
 LA English
 LAP English
 TL German; English; French
 PIT EPA2 Application published without search report
 PI EP-----1625990 A2 20060215
 DS AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HU IE IS IT LI LT LU LV MC NL
 PL PT RO SE SI SK TR
 EXTENSION STATES: AL BA HR MK YU
 AI 2005EP-0466008 A 20050810
 PRAI 2004MY-0003274 A 20040812
 IPCI B62B-0001-22 [I,A]
 B62B-0001-00 [I,C*]

ABEN

The present invention is an improved wheelbarrow with a releasable container connected to a releasable locking system for easy pouring and requiring small leverage to lift the container. The improved wheelbarrow comprising a lever mounted directly on the handle part of the wheelbarrow support frame for easily release the container during removing load process. The lever is joined to a pivotal hook which is mounted on the body of the support frame by a cable. The container includes a fixture on the lower part rear end of the container. This is to secure the container to the releasable locking system when in loading or moving position. With the grasping of the lever, a tension force is formed and thus pulled the pivotal hook backward away from the hooked position. This releases the container from its secured position and can be easily lifted for emptying purposes.

(image, imgaf001.tif, drawing)

MCLMEN

A wheelbarrow with releasable container comprising:

a support frame;

a pair of handle connected to said support frame of said wheelbarrow;

a container pivotably mounted to said support frame at the lower part front end of said container;

a fixture mounted at the rear end of said container;

a pivotable hook mounted at the body of said handle; and

a lever disposed at the rear end of said handle, whereby said fixture, pivotable hook and said lever collectively forming a releasable locking system and said pivotable hook is responsive to the lever to engage with said fixture when said container is in attached position and disengage with said fixture when said container is in released position.

DISPLAY STD (STN format)

AN 2007:56845 EPFULL EDP 20080227 ED 20080227 UP 20080227
 DUPD 20080227 DUPW 200809
 TIEN PIEZOACTUATOR WITH A CASING.
 TIFR PIEZO-ACTIONNEUR COMPORTANT UN GAINAGE.
 TIDE PIEZOAKTOR MIT EINER UMMANTELUNG.
 IN SCHAICH, Udo, Keltenweg 57, 70378 Stuttgart, DE;
 KIONTKE, Martin, Schubartstrasse 3a, 70825 Korntal-Muenchingen, DE;
 KOERKEMEYER, Jens, Alexandrinenplatz 1, 71686 Remseck, DE
 PA Robert Bosch GmbH, Postfach 30 02 20, 70442 Stuttgart, DE
 PAN 8085980
 DT Patent
 LAF German
 LA German
 LAP German
 TL German; English; French
 PIT WOA2 International application published without search report
 PI WO 2007122153 A2 20071101
 DS AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HU IE IS IT LI LT LU LV MC MT
 NL PL PT RO SE SI SK TR
 EXTENSION STATES: AL BA HR MK YU
 AI EP 2007-728229 A 20070418
 WO 2007-EP53767 A 20070418
 PRAI DE 2006-102006019047 A 20060425
 IPCI H01L0041-053 [I,A]; H01L0041-083 [I,A]
 H01L0041-00 [I,C*]; H01L0041-083 [I,C*]